

Place of PTO-1499 Form		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number		10/799,836	
		Filing Date		03/12/2004	
		Applicant(s)		Saini et al.	
		Art Unit		2879 <i>2881</i>	
		Examiner Name		<i>To be Assigned J. Smith</i>	
SHEET 1 OF 1		Attorney Docket Number		34003.110	


U. S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date MM/YYYY	Name of Patentee or Applicant of Cited Document
<i>[Handwritten signature]</i>	AA	5963788	10/1999	Barron et al.
	AB	6103399	08/2000	Smela et al.
	AC	6219254	04/2001	Akerling et al.
	AD	6300156	10/2001	Decker et al.
	AE	6398280	06/2002	Parker et al.
	AF	2002/0125208	09/2002	Christenson et al.
	AG	6561725	05/2003	Ellis et al.
	AH	6672795	01/2004	Ellis et al.
	AI	6745567	06/2004	Mercanzini
	AJ	6762116	07/2004	Skidmore

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

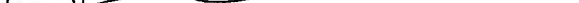
NON-PATENT LITERATURE DOCUMENTS		
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume- issue number(s), publisher, city/country where published
<i>[Handwritten signature]</i>	AK	Murray et al., "Advances in Arrayed Microcolumn Lithography", Journal of Vacuum Science and Technology. B, Microelectronics and Nanometer Structures Processing, Measurement and Phenomena: An Official Publication of the American Vacuum Society, Volume 18 (6), November/December 2000, pages 3099-3104. (IRN10495228)

Examiner Signature	<i>[Handwritten signature]</i>	Date Considered	<i>05/05/05</i>
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Examiner Signature		Date Considered	05/05/05
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